

Notice of References Cited	Application/Control No. <i>09/878,556</i>	Applicant(s)/Patent Under Reexam <i>Iyer et al.</i>	
	Examiner <i>Tauk Chen</i>	Art Unit <i>2813</i>	Page <u>1</u> of <u>1</u>

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NON-PATENT DOCUMENTS		
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